Search Notes

Application/Control No.	Applicant(s Reexamina
10/61/ 716	CDEENII\/A

10/614,716 Examiner

Emmanuel S. Luk

Applicant(s)/Patent under Reexamination

SREENIVASAN ET AL.

Art Unit

1722

	SEARCHED				
Class	Subclass	Date	Examiner		
425	385	5/29/2006	EL		
425	177	5/29/2006	EL		
425	432	5/29/2006	EL		
425	810	5/29/2006	EL		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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